

2022 USC and EE of Yonsei Joint International Workshop of Yonsei University Y-BASE AI Group

Research of Digital Contact-Tracing

Date : **May 18th, 2022** (2022 년 5 월 18 일 (수))

Location : **Engineering Executive Program room (Yonsei Engineering Building 2, B201)**

(연세대학교 제 2 공학관, B201, 공학대학원 최고위과정 강의실)

In order to solve various urban problems such as traffic congestion and epidemic prevention, various new technologies such as information and communication technology and big data have been introduced. The current smart city technology has developed into a convergence technology composed of various element technologies. Among them, the importance of digital contact-tracing is been recently noted. Amid the COVID-19 pandemic, digital contact-tracing has been highlighted as a critical technology to stop COVID-19 transmission.

In this workshop, we will discuss the forefront of various technologies that compose digital contact-tracing. In addition, there are new problems caused by the advancement of digital contact-tracing technology, such as security and privacy. We will also cover these topics, and discuss the blueprint of future digital contact-tracing studies.

	GMT+9 Seoul	Session	Presenter
May 18 (Wed)	12:55 ~ 13:00	Opening	Kwanghoon Sohn (Yonsei University)
	13:00 ~ 13:35	Deep joint image filtering	Bumsub Ham (Yonsei University)
	13:35 ~ 14:10	Location & Privacy: Past, Present and Future -- A Spatial Data Perspective	Cyrus Shahabi (University of Southern California)
	14:10 ~ 14:45	Benefits and Risks of Sensing for Emerging Internet-of-Things Applications	Jun Han (Yonsei University)
	14:45 ~ 15:20	New Eyes on Our Cities: Issues and Challenges of Smart City Monitoring	Seon Ho Kim (University of Southern California)
	15:20 ~ 16:05	Conditional Biometrics Embedding Learning For Periocular Recognition	Andrew Teoh (Yonsei University)
	16:05 ~ 16:10	Closing	Sanghoon Lee (Yonsei University)

HOSTs Yonsei University Y-BASE AI Group, Yonsei University AI-Cluster

Organizer Yonsei University Brain Korea 21 FOUR Program, Y-BASE R&E Institute